

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components,

Assemblies, Related Materials and Processes For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

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1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military accelerated environment reliability stress tests (Including: Pre-condition / MSL / Accelerated Temperature-Humidity test / Temperature- Humidity with bias test / Temperature Cycling test / Power and temperature cycling / Temperature storage test / IOL / Salt)	J-STD-020, JESD22-A101/A102/A106/A107/A110/A113/ A118/A119; IEC-60068-2-1/2/3/14/ 38/52, MIL-STD-202/750/810/883, JESD JP001; EIA-364-32C, EIAJ ED-4701, AEC-Q200-001 /004; AEC-Q005/Q006,	Or customer specified test
Consumer/ Commercial / Industrial (JESD 47) and Automotive / Military accelerated lifetime simulation tests. (Including : Temperature, Bias, and Operating Life test / early life failure rate / Endurance and Data retention test / Electro-Migration / Short circuit / Miscellaneous test / Gate Leakage test)	JESD22-A108/A117, JESD61, MIL-STD-202/750/810/883, AEC-Q100-005/006/008/012, AEC-Q101-004/006, Customer standards	Or customer specified test
Failure and material analysis of semiconductor IC (TEM / SEM / DUAL BEAM FIB), electronic components and PCB/PCBA, including FIB (Focused Ion Beam), Electrical Analysis, Sample Preparation (Decap, X-section, etc), NDE (Non- destructive Engineering), Physical & Chemical Analysis (Including Hazardous Substances) and IC package.	IPC-TM-650, IPC-610, J-STD-020, JEDEC-C201, EIA-469, IEC62321, EN14582,	Or customer specified test
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military electromagnetic compatibility and electrostatic discharge test. (Including : HBM / MM / CDM / Latch Up / ESD Gun)	IEC 61967/1-3, JESD22-A114/A115/C101, EIA/JESD78, ANSI JEDEC ESDA JS001/JS002; ISO-10605, AEC-Q100-002/003/004/011, AEC-Q101-001/002/005, AEC-Q200-002, JEITA ED4701; IEC61000-4-2, MIL-STD-202/750/810/883	Or customer specified test

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